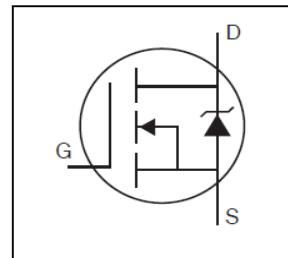


## Features

- Advanced Process Technology
- Key Parameters Optimized for PDP Sustain, Energy Recovery and Pass Switch Applications
- Low  $E_{PULSE}$  Rating to Reduce Power Dissipation in PDP Sustain, Energy Recovery and Pass Switch Applications
- Low  $Q_G$  for Fast Response
- High Repetitive Peak Current Capability for Reliable Operation
- Short Fall & Rise Times for Fast Switching
- 150°C Operating Junction Temperature for Improved Ruggedness
- Repetitive Avalanche Capability for Robustness and Reliability

HEXFET® Power MOSFET

Key Parameters		
$V_{DS}$ max	250	V
$V_{DS}$ (Avalanche) typ.	300	V
$R_{DS(ON)}$ typ. @ 10V	38	$\text{m}\Omega$
$I_{RP}$ max @ $T_C = 100^\circ\text{C}$	32	A
$T_J$ max	150	$^\circ\text{C}$



G	D	S
Gate	Drain	Source

## Description

This HEXFET® Power MOSFET is specifically designed for Sustain; Energy Recovery & Pass switch applications in Plasma Display Panels. This MOSFET utilizes the latest processing techniques to achieve low on-resistance per silicon area and low  $E_{PULSE}$  rating. Additional features of this MOSFET are 150°C operating junction temperature and high repetitive peak current capability. These features combine to make this MOSFET a highly efficient, robust and reliable device for PDP driving applications

Base Part Number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
IRFI4229PbF	TO-220 Full-Pak	Tube	50	IRFI4229PbF

## Absolute Maximum Ratings

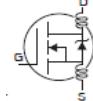
Symbol	Parameter	Max.	Units
$V_{GS}$	Gate-to-Source Voltage	$\pm 30$	V
$I_D$ @ $T_C = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS}$ @ 10V	19	A
$I_D$ @ $T_C = 100^\circ\text{C}$	Continuous Drain Current, $V_{GS}$ @ 10V	12	
$I_{DM}$	Pulsed Drain Current ①	72	
$I_{RP}$ @ $T_C = 100^\circ\text{C}$	Repetitive Peak Current ⑤	32	W
$P_D$ @ $T_C = 25^\circ\text{C}$	Maximum Power Dissipation	46	
$P_D$ @ $T_C = 100^\circ\text{C}$	Maximum Power Dissipation	18	
	Linear Derating Factor	0.37	W/ $^\circ\text{C}$
$T_J$	Operating Junction and Storage Temperature Range	-40 to + 150	$^\circ\text{C}$
$T_{STG}$		300	
	Soldering Temperature, for 10 seconds (1.6mm from case)	10 lbf-in (1.1N·m)	
	Mounting torque, 6-32 or M3 screw		

## Thermal Resistance

Symbol	Parameter	Typ.	Max.	Units
$R_{QJC}$	Junction-to-Case ④	—	2.73	$^\circ\text{C}/\text{W}$
$R_{QJA}$	Junction-to-Ambient	—	65	

**Electrical Characteristics @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	250	—	—	V	$V_{GS} = 0V, I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	340	—	mV/°C	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
$R_{DS(\text{on})}$	Static Drain-to-Source On-Resistance	—	38	46	$\text{m}\Omega$	$V_{GS} = 10V, I_D = 11\text{A}$
$V_{GS(\text{th})}$	Gate Threshold Voltage	3.0	—	5.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
$\Delta V_{GS(\text{th})}/\Delta T_J$	Gate Threshold Voltage Temp. Coefficient	—	-12	—	mV/°C	
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	20	$\mu\text{A}$	$V_{DS} = 250V, V_{GS} = 0V$
		—	—	200		$V_{DS} = 250V, V_{GS} = 0V, T_J = 150^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	$\text{nA}$	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS} = -20V$
$g_{fs}$	Forward Trans conductance	26	—	—	S	$V_{DS} = 25V, I_D = 11\text{A}$
$Q_g$	Total Gate Charge	—	73	110	$\text{nC}$	$I_D = 11\text{A}, V_{DS} = 125V$
$Q_{gd}$	Gate-to-Drain Charge	—	24	—		$V_{GS} = 10V$
$t_{d(on)}$	Turn-On Delay Time	—	18	—	$\text{ns}$	$V_{DD} = 125V, V_{GS} = 10V$ $I_D = 11\text{A}$ $R_G = 2.4\Omega$ See Fig. 22
$t_r$	Rise Time	—	17	—		
$t_{d(off)}$	Turn-Off Delay Time	—	32	—		
$t_f$	Fall Time	—	13	—		
$t_{st}$	Shoot Through Blocking Time	100	—	—	ns	$V_{DD} = 200V, V_{GS} = 15V, R_G = 5.1\Omega$
$E_{\text{PULSE}}$	Energy per Pulse	—	770	—	$\mu\text{J}$	$L = 220\text{nH}, C = 0.3\mu\text{F}, V_{GS} = 15V$
		—	1380	—		$V_{DD} = 200V, R_G = 5.1\Omega, T_J = 25^\circ\text{C}$ $L = 220\text{nH}, C = 0.3\mu\text{F}, V_{GS} = 15V$ $V_{DD} = 200V, R_G = 5.1\Omega, T_J = 100^\circ\text{C}$
$C_{iss}$	Input Capacitance	—	4480	—	$\text{pF}$	$V_{GS} = 0V$ $V_{DS} = 25V$ $f = 1.0\text{MHz}$ $V_{GS} = 0V, V_{DS} = 0V \text{ to } 200V$
$C_{oss}$	Output Capacitance	—	400	—		
$C_{rss}$	Reverse Transfer Capacitance	—	100	—		
$C_{oss \text{ eff.}}$	Effective Output Capacitance	—	270	—		
$L_D$	Internal Drain Inductance	—	4.5	—	$\text{nH}$	Between lead, 6mm (0.25in.) from package and center of die contact
$L_S$	Internal Source Inductance	—	7.5	—		


**Avalanche Characteristics**

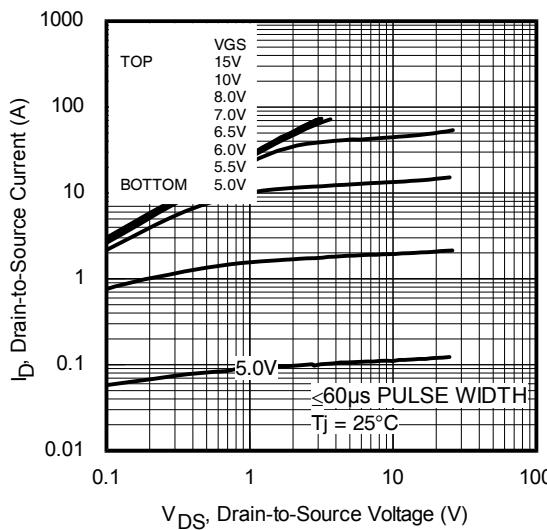
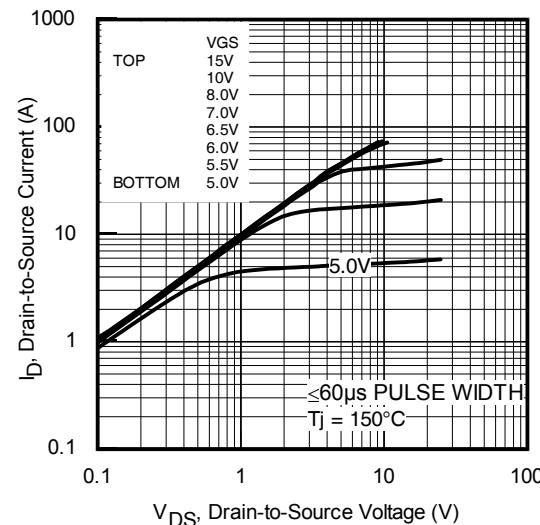
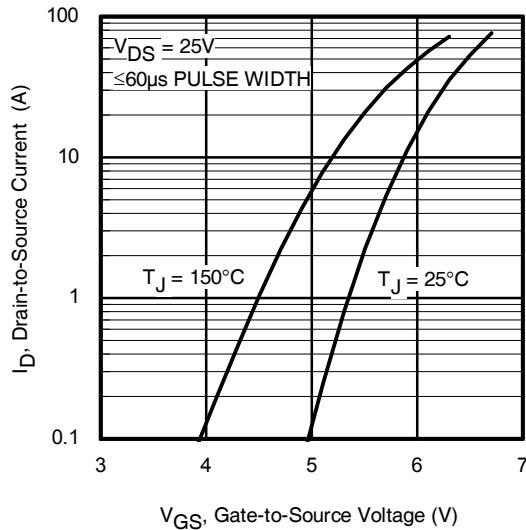
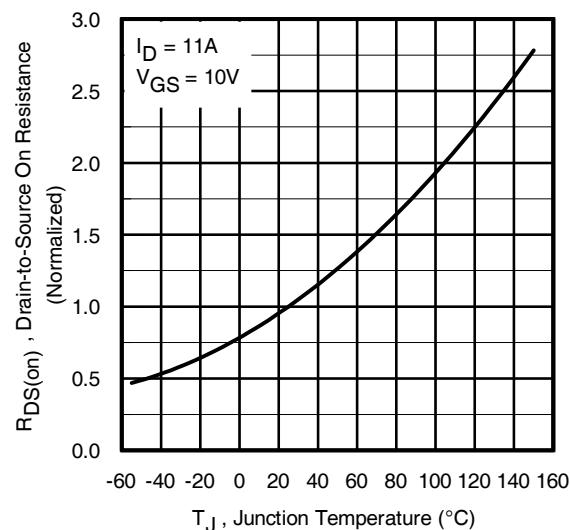
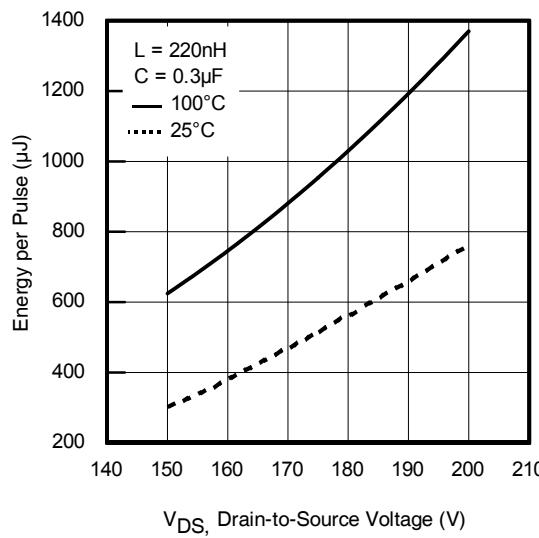
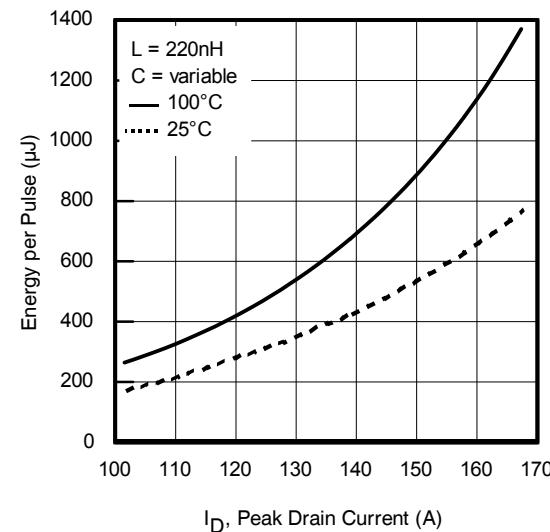
	Parameter	Typ.	Max.	Units
$E_{AS}$	Single Pulse Avalanche Energy ②	—	110	mJ
$E_{AR}$	Repetitive Avalanche Energy ①	—	4.6	
$V_{DS(\text{Avalanche})}$	Repetitive Avalanche Voltage ①	300	—	V
$I_{AS}$	Avalanche Current ②	—	11	A

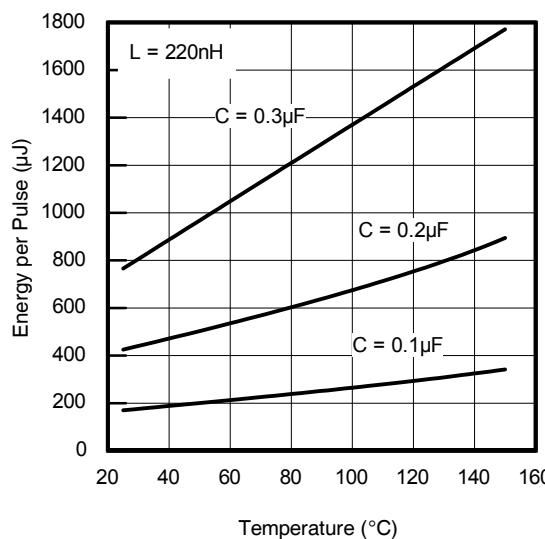
**Diode Characteristics**

	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S @ T_C = 25^\circ\text{C}$	Continuous Source Current (Body Diode)	—	—	18	A	MOSFET symbol showing the integral reverse p-n junction diode.
	Pulsed Source Current (Body Diode) ①	—	—	72		
$V_{SD}$	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}, I_S = 11\text{A}, V_{GS} = 0V$ ③
$t_{rr}$	Reverse Recovery Time	—	120	180	ns	$T_J = 25^\circ\text{C}, I_F = 11\text{A}, V_{DD} = 50V$ $dI/dt = 100\text{A}/\mu\text{s}$ ③
$Q_{rr}$	Reverse Recovery Charge	—	540	810	nC	

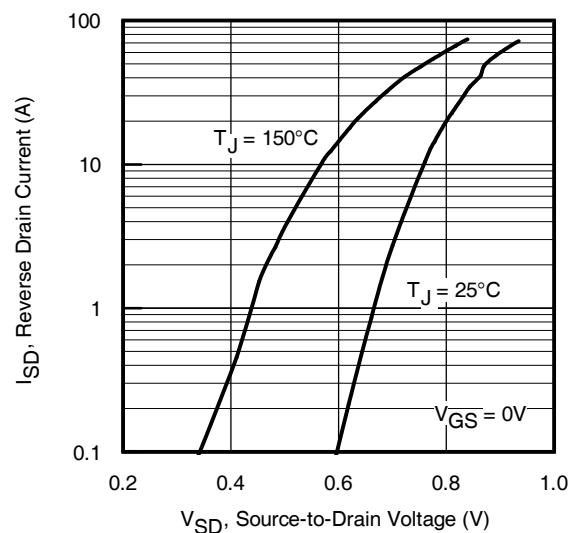
**Notes:**

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② starting  $T_J = 25^\circ\text{C}, L = 1.9\text{mH}, R_G = 25\Omega, I_{AS} = 11\text{A}$ .
- ③ Pulse width  $\leq 400\mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- ④  $R_\theta$  is measured at  $T_J$  of approximately  $90^\circ\text{C}$ .
- ⑤ Half sine wave with duty cycle = 0.25,  $t_{on}=1\mu\text{sec}$ .

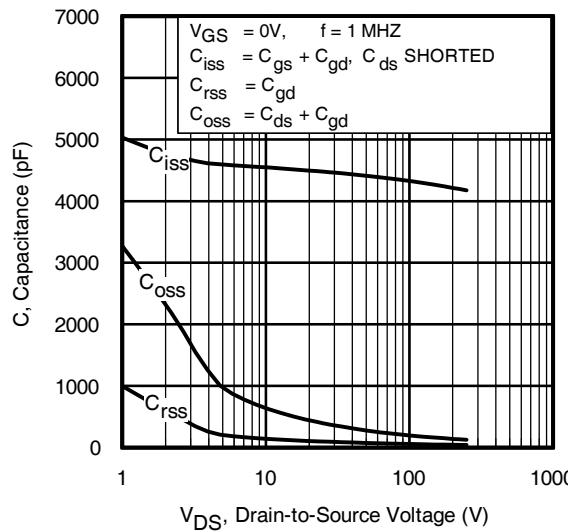

**Fig. 1.** Typical Output Characteristics

**Fig. 2.** Typical Output Characteristics

**Fig. 3.** Typical Transfer Characteristics

**Fig. 4.** Normalized On-Resistance vs. Temperature

**Fig 5.** Typical  $E_{PULSE}$  vs. Drain-to-Source Voltage

**Fig 6.** Typical  $E_{PULSE}$  vs. Drain Current



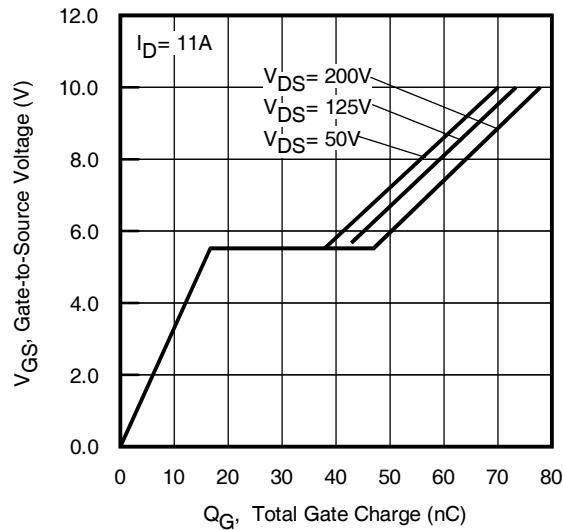
**Fig. 7.** Typical  $E_{\text{PULSE}}$  vs. Temperature



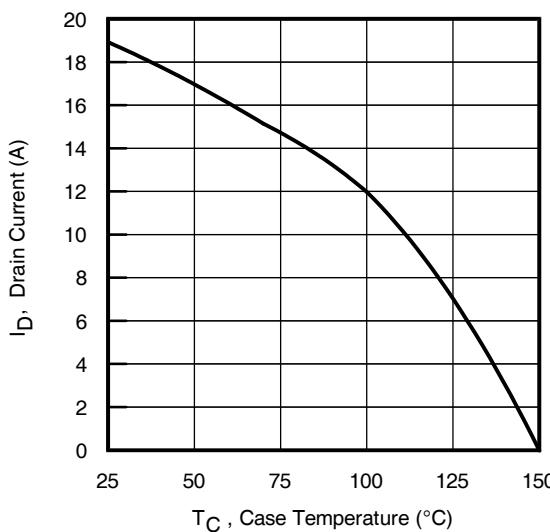
**Fig 8.** Typical Source-Drain Diode Forward Voltage



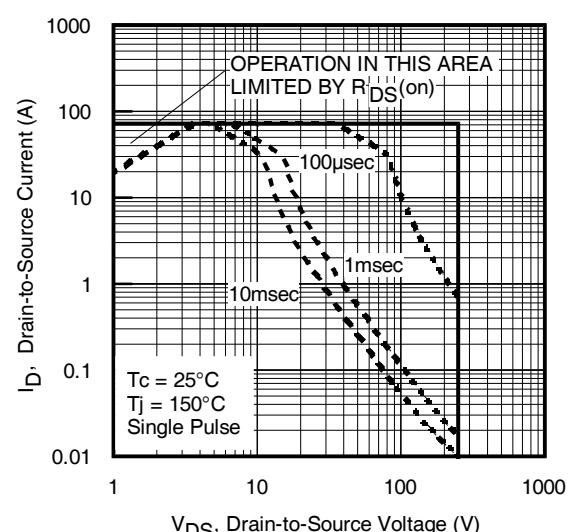
**Fig 9.** Typical Capacitance vs. Drain-to-Source Voltage



**Fig 10.** Typical Gate Charge vs. Gate-to-Source Voltage



**Fig 11.** Maximum Drain Current vs. Case Temperature



**Fig 12.** Maximum Safe Operating Area

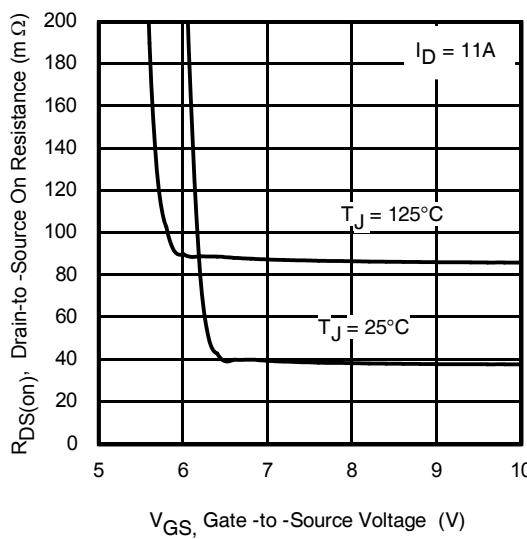


Fig. 13. On-Resistance Vs. Gate Voltage

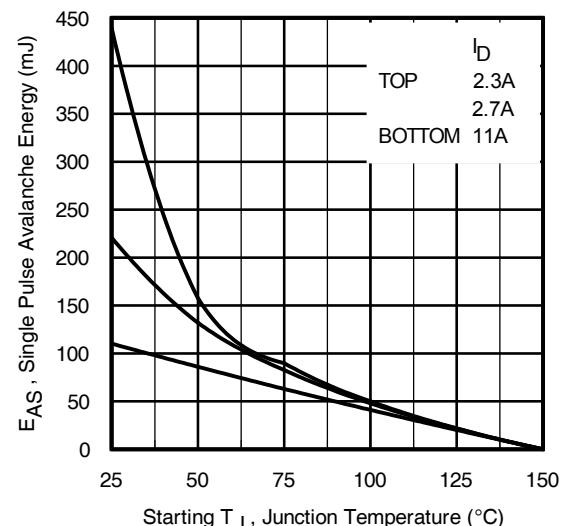


Fig. 14. Maximum Avalanche Energy Vs. Temperature

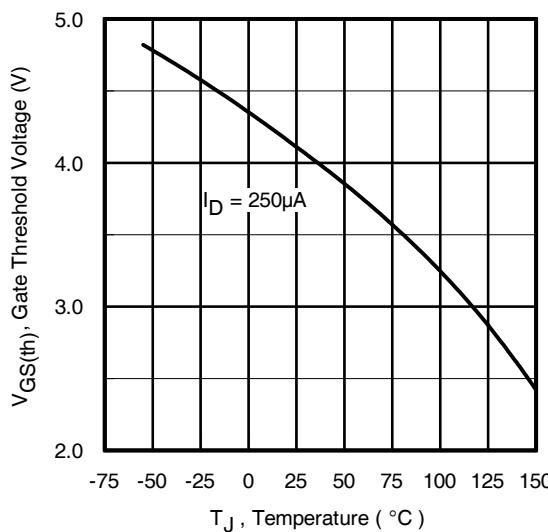


Fig. 15. Threshold Voltage vs. Temperature

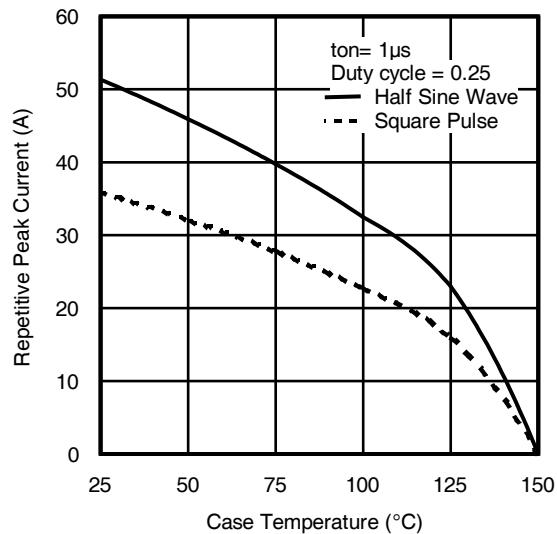


Fig. 16. Typical Repetitive peak Current vs. Case temperature

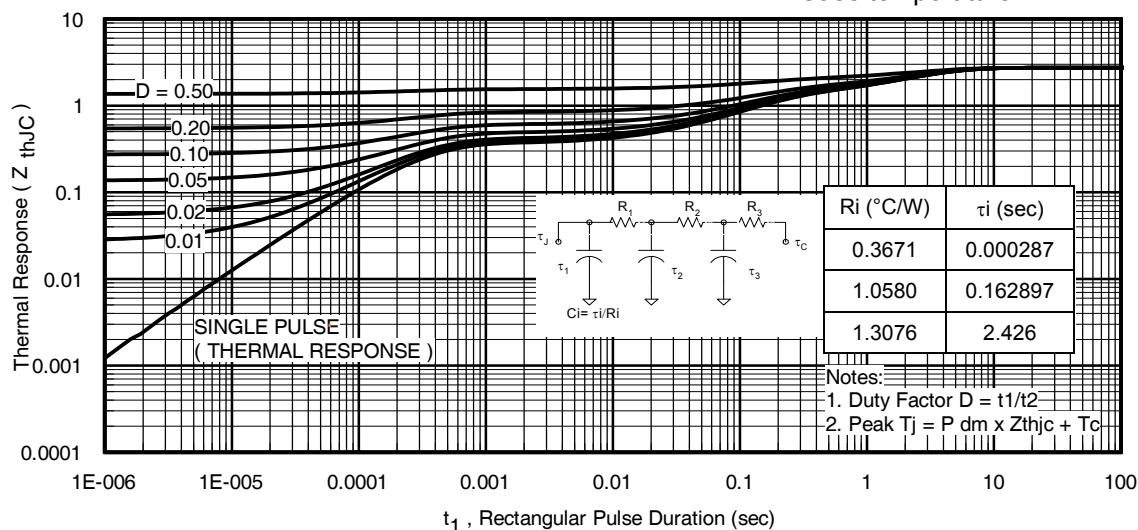
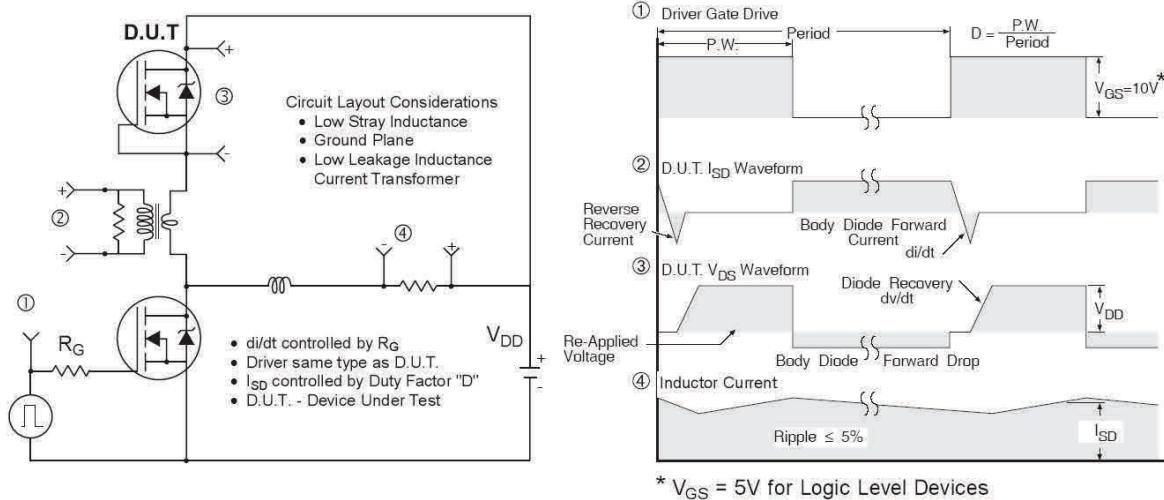
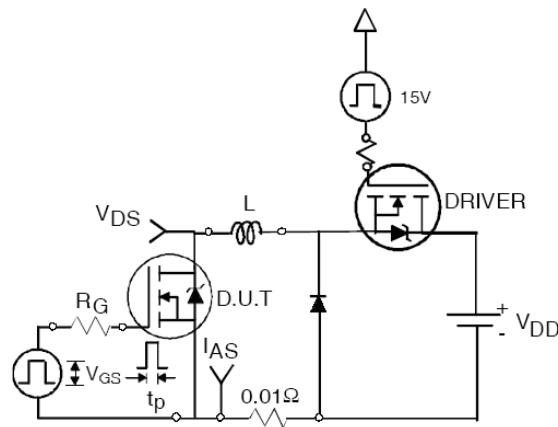


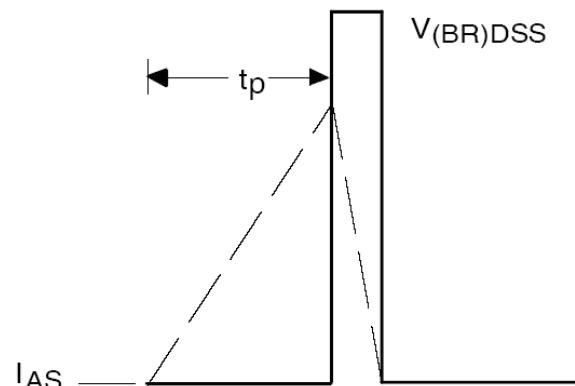
Fig 17. Maximum Effective Transient Thermal Impedance, Junction-to-Case



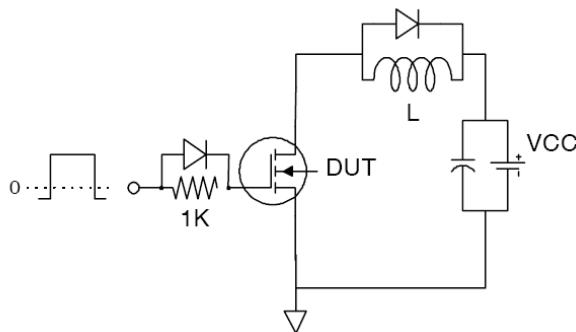
**Fig 18.** Diode Reverse Recovery Test Circuit for N-Channel HEXFET® Power MOSFETs



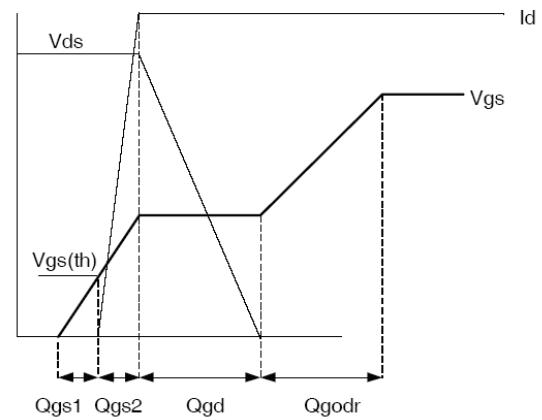
**Fig 19a.** Unclamped Inductive Test Circuit



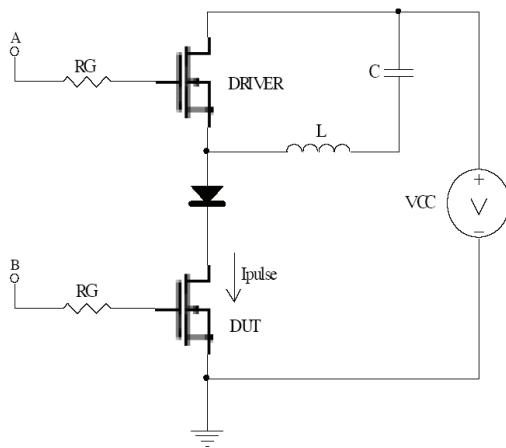
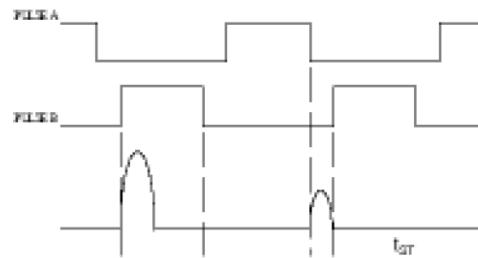
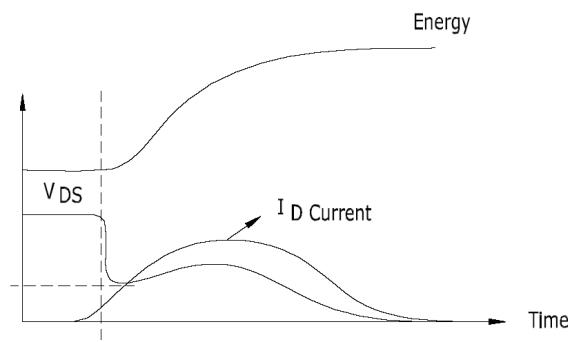
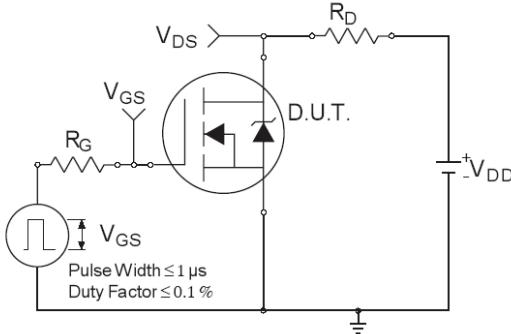
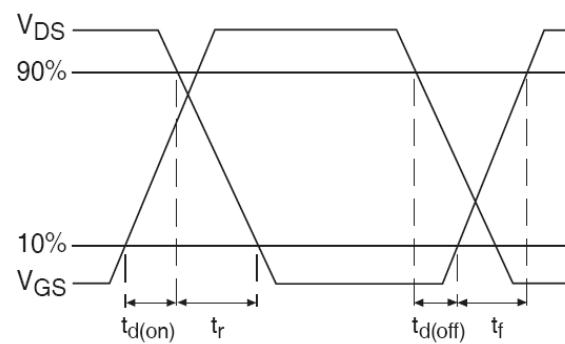
**Fig 19b.** Unclamped Inductive Waveforms



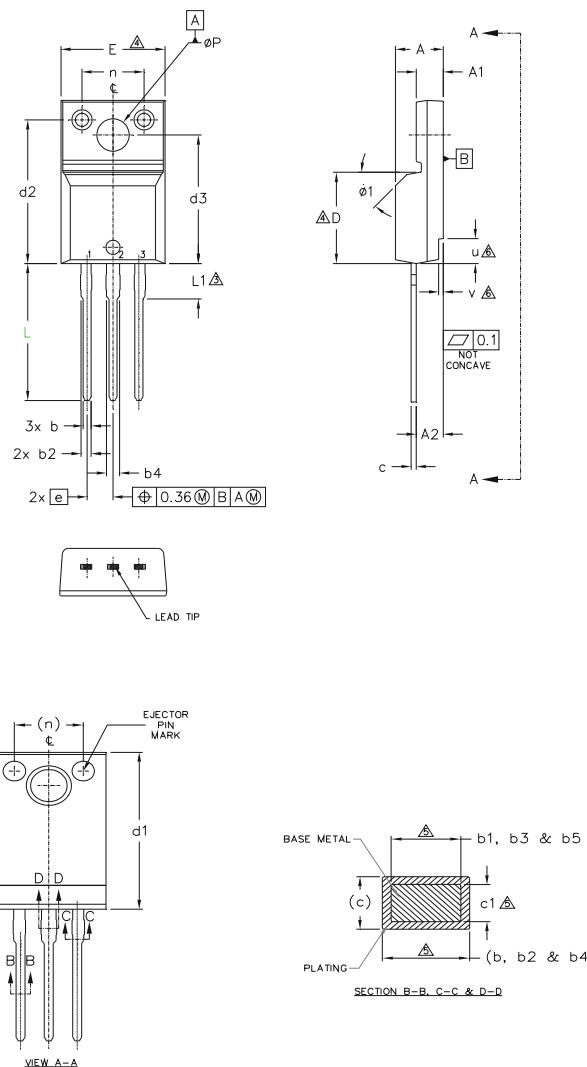
**Fig 20a.** Gate Charge Test Circuit



**Fig 20b.** Gate Charge Waveform

**Fig 21a.**  $t_{st}$  and  $E_{PULSE}$  Test Circuit**Fig 21b.**  $t_{st}$  Test Waveforms**Fig 21c.**  $E_{PULSE}$  Test Waveforms**Fig 22a.** Switching Time Test Circuit**Fig 22b.** Switching Time Waveforms

## TO-220 Full-Pak Package Outline (Dimensions are shown in millimeters (inches))



S Y M B O L	DIMENSIONS				N O T E S	
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	4.57	4.83	.180	.190		
A1	2.57	2.82	.101	.111		
A2	2.51	2.92	.099	.115		
b	0.61	0.94	.024	.037		
b1	0.61	0.89	.024	.035	5	
b2	0.76	1.27	.030	.050		
b3	0.76	1.22	.030	.048	5	
b4	1.02	1.52	.040	.060		
b5	1.02	1.47	.040	.058	5	
c	0.33	0.63	.013	.025		
c1	0.33	0.58	.013	.023	5	
D	8.66	9.80	.341	.386	4	
d1	15.80	16.13	.622	.635		
d2	13.97	14.22	.550	.560		
d3	12.29	12.93	.484	.509		
E	9.63	10.74	.379	.423	4	
e	2.54	BSC	.100	BSC		
L	13.21	13.72	.520	.540		
L1	3.10	3.68	.122	.145	3	
n	6.05	6.60	.238	.260		
ØP	3.05	3.45	.120	.136		
u	2.39	2.49	.094	.098	6	
v	0.41	0.51	.016	.020	6	
Ø1	—	45°	—	45°		

LEAD ASSIGNMENTSHEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE

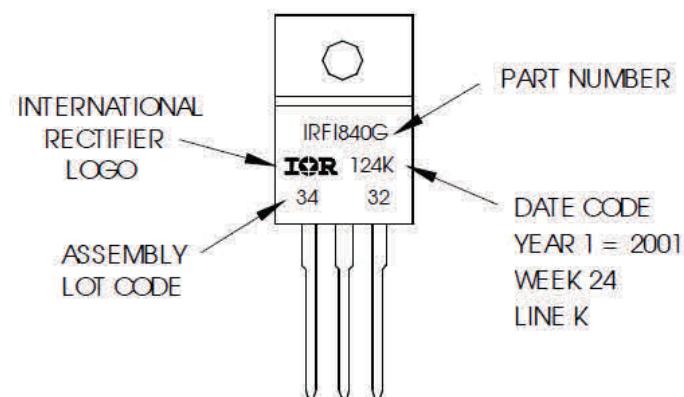
IGBTs, CoPACK

- 1.- GATE
- 2.- COLLECTOR
- 3.- Emitter

## TO-220 Full-Pak Part Marking Information

EXAMPLE: THIS IS AN IRFI840G  
WITH ASSEMBLY  
LOT CODE 3432  
ASSEMBLED ON WV 24, 2001  
IN THE ASSEMBLY LINE "K"

Note: "P" in assembly line position  
indicates "Lead-Free"



TO-220AB Full-Pak packages are not recommended for Surface Mount Application.

Note: For the most current drawing please refer to website at <http://www.irf.com/package/>

**Qualification Information**

<b>Qualification Level</b>	Industrial (per JEDEC JESD47F) <sup>†</sup>	
<b>Moisture Sensitivity Level</b>	TO-220 Full-Pak	N/A
<b>RoHS Compliant</b>	Yes	

<sup>†</sup> Applicable version of JEDEC standard at the time of product release.

**Revision History**

Date	Comments
04/27/2017	<ul style="list-style-type: none"> <li>• Changed datasheet with Infineon logo - all pages.</li> <li>• Corrected Package Outline on page 8.</li> <li>• Added disclaimer on last page.</li> </ul>

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Trademarks updated November 2015

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**Document reference**

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